

**Search Notes**

Application/Control No.

10/520,516

Examiner

Scott Bushey

Applicant(s)/Patent under  
Reexamination

OOYACHI ET AL.

Art Unit

1724

**SEARCHED**

Class	Subclass	Date	Examiner
261	36.1,37,38 64.3,72.1, 79.2,94,95		
261	96,100		
261	101,102		
261	104,121.1		
261	122.1		
261	Dig. 7		
366	337-339	4/9/2007	CSB

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Inventor Name Search and Text Search	4/9/2007	CSB